Search Notes

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10/784,578

ABE, HIROSHI

Applicant(s)/Patent under Reexamination

Examiner

Art Unit

Mark J. Beauchaine

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	SEAR	CHED	
Class	Subclass	Date	Examiner
221	64,174, 178,179,	9/26/2005	МЈВ
194	350,353	9/26/2005	MJB
453	1,2,16-18		
	49,63	9/26/2005	MJB
221	180	9/27/2005	MJB
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INT	INTERFERENCE SEARCHED			
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EAST 2.1.0 - USPAT, USPGPUB, EPO, JPO, DERWENT	9/26/2005	мјв
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